

	Type	L #	Hits	Search Text	Dbs	Time Stamp	Comments	Error Definition	Err ors
1	BRS	L1	434	(integrate\$1 or wafer\$1 or "IC"chip\$1 or printed near\$3 circuits) same(aperture near\$ first) and aperture near\$ second	USPAT	2004/01/26 14:59			0
2	BRS	L2	299	(integrate\$1 or wafer\$1 or "IC"chip\$1 or printed near\$3 circuits) same(aperture near\$ first) same (aperture near\$ second)	USPAT	2004/01/26 15:00			0
3	BRS	L4	0	3 and (align\$3 near\$3 (open\$4 or hole\$1))same aperture	USPAT	2004/01/26 15:04			0
4	BRS	L6	0	5 and(detector\$2 or "CCD" or imager or imaging near\$3 device or image near\$3 pickup)	USPAT	2004/01/26 15:04			0
5	BRS	L5	13	2 and (align\$3 near\$3 (open\$4 or hole\$1))same aperture	USPAT	2004/01/26 15:30			0
6	BRS	L7	69030	(inspec\$4 or detec\$4)same (integrate\$1 or wafer\$1 or "IC"chip\$1 or printed near\$3 circuits)	USPAT	2004/01/26 15:44			0
7	BRS	L8	3404	7 same (void\$1 or defect\$2)	USPAT	2004/01/26 15:45			0
8	BRS	L9	3	8 and (align\$3 near\$3 (open\$4 or hole\$1))same aperture	USPAT	2004/01/26 15:45			0
9	BRS	L10	1884	382/141,145,147,149,151;438 /16.ccls.	USPAT	2004/01/26 15:44			0
10	BRS	L11	781	10 and(inspec\$4 or detec\$4)same (integrate\$1 or wafer\$1 or "IC"chip\$1 or printed near\$3 circuits)	USPAT	2004/01/26 15:44			0
11	BRS	L12	449	11 and (void\$1 or defect\$2)	USPAT	2004/01/26 15:45			0

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Err ors
12	BRS	L13	0	12 and (align\$3 near3 (open\$4 or hole\$1))same aperture	USPAT	2004/01/26 16:10			0
13	BRS	L14	1	11 and (align\$3 near3 (open\$4 or hole\$1))same aperture	USPAT	2004/01/26 15:46			0
14	BRS	L3	14	2 same(detector\$2 or "CCD" or imager or imaging near3 device or image near3 pickup)	USPAT	2004/01/26 15:55			0
15	BRS	L16	0	15 and (align\$3 near3 (open\$4 or hole\$1))same aperture	USPAT	2004/01/26 16:10			0
16	BRS	L17	0	15 and aperture near3 first and aperture near3 second	USPAT	2004/01/26 16:11			0
17	BRS	L15	105	((((inspect\$4 or detect\$4)same (integrate\$1 or wafer\$1 or "IC"chip\$1 or printed near3 circuits)) same (void\$1 or defect\$2)) same(x-ray or x-rays or x-raying or x-rayed))	USPAT	2004/01/26 16:12			0